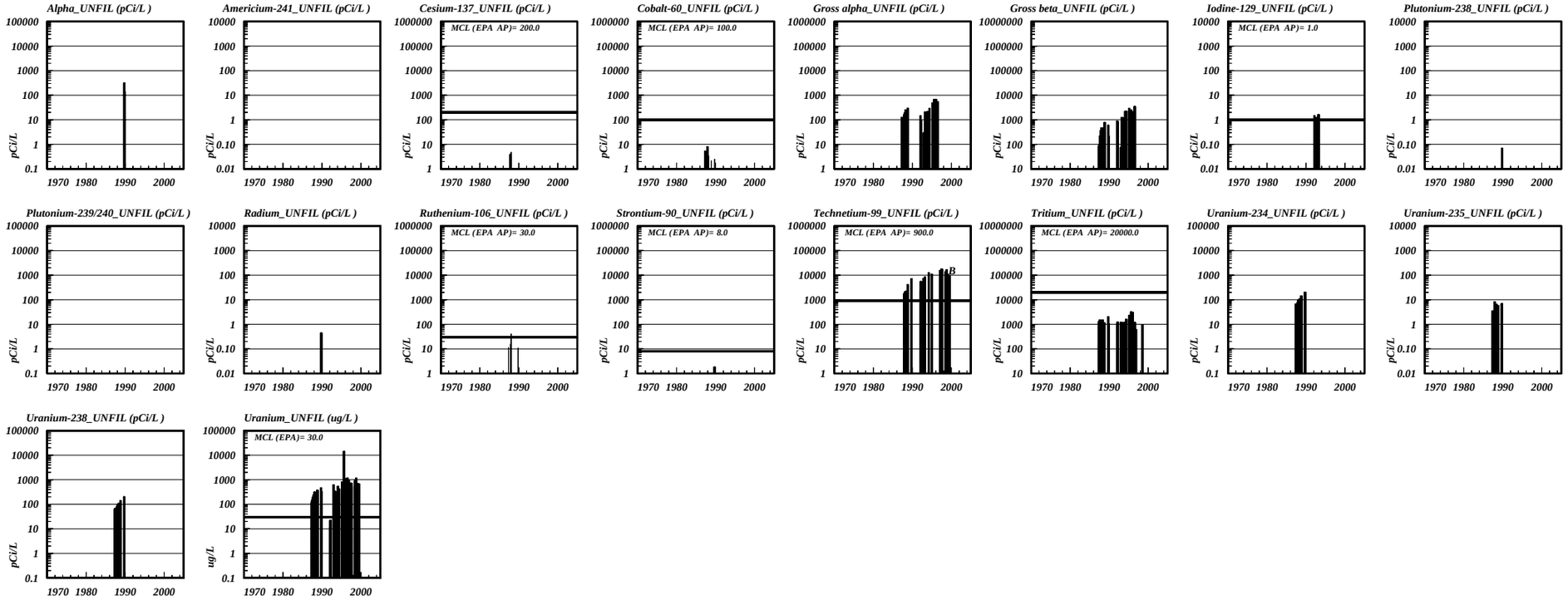
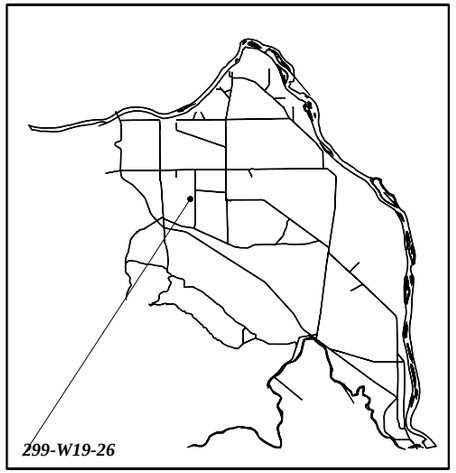
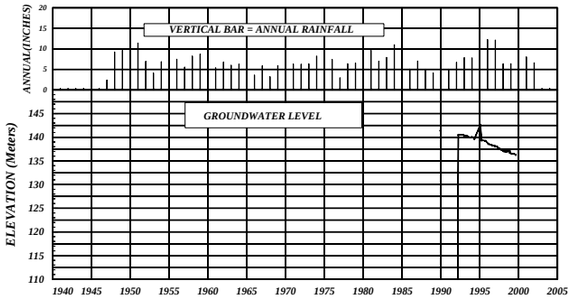
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-200-299 WELL#=299-W19-26

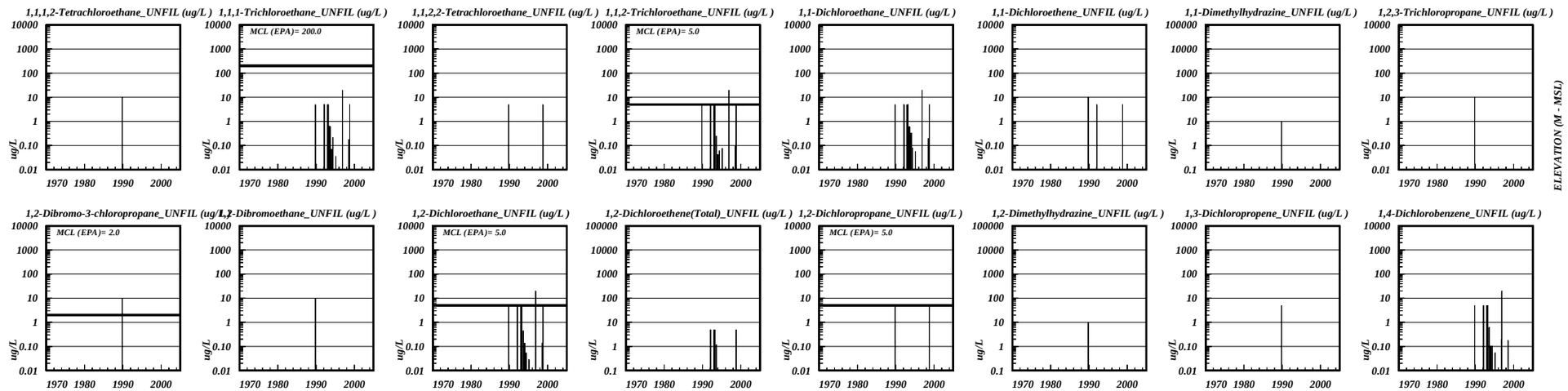
RADIONUCLIDES

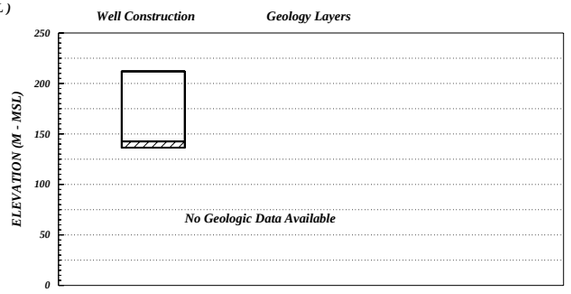






VOLATILE ORGANIC COMPOUNDS





WELLNAME=299-W19-26 WELLID=A7747

Well Type=STANDARD Well purpose=GROUNDWATER
Owner=DOE ContactBHI Well Adm Compliance=NON-COMPLIANT
X_coor= 567845.50 Y-coor= 134894.70 Datum=NAD83(91) Date Survey= 6/9/1994
Elevation= 212.000 Datum=NAVD88 Date Survey=06/09/94
Ref_Point_Desc=TOP OF CASING Ref_Point_side=N Contractor=USACE(JECA)
Total Number of Screen Intervals=1
Screen#=1 Screen_diam= 5.00 in Top= 69.49 Bottom= 75.59 m Slot_size= 0.00
Screen_material=Stainless Steel

LABORATORY QUALIFIER FLAGS in HEIS are *, >, B, C, D, E, J, L, P, Q, R, W, X, Y, and Z: Review Document. Main Flags are : J=Estimated value:L=Value between IDL and CRQL (estimated):T=Tentatively identified compound:
EPA-IGR=EPA-Implementation Guidance for Radionuclides: WAC=Washington Administrative Code:

EXPLANATION: THICK FILLED BARS=Value Above Detection Limit:THIN BARS=Value Below Detection Limit:HATCHED BARS=Value With Data Qualifier Flag

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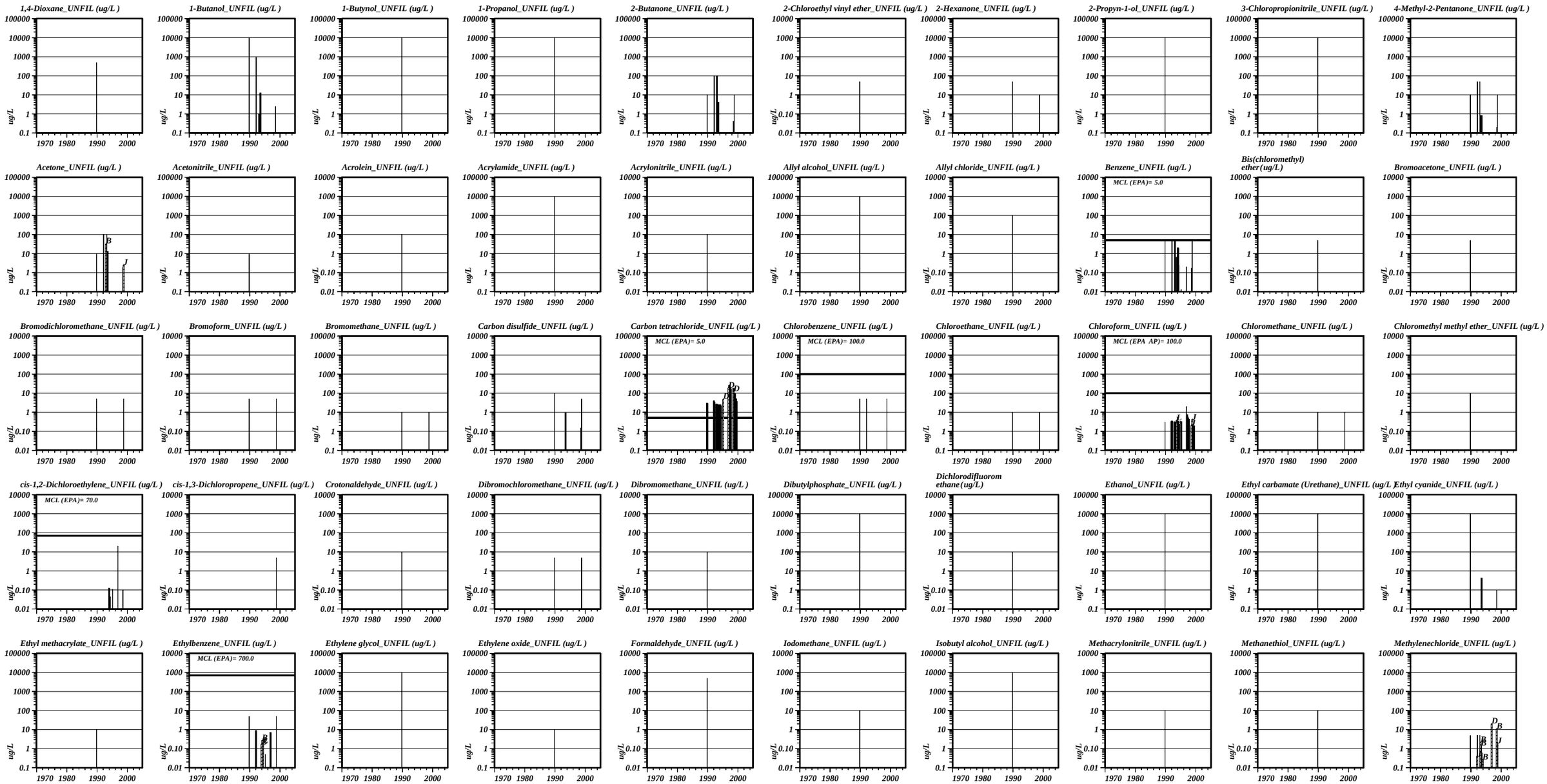
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-200-299 WELL#=299-W19-26

VOLATILE ORGANIC COMPOUNDS



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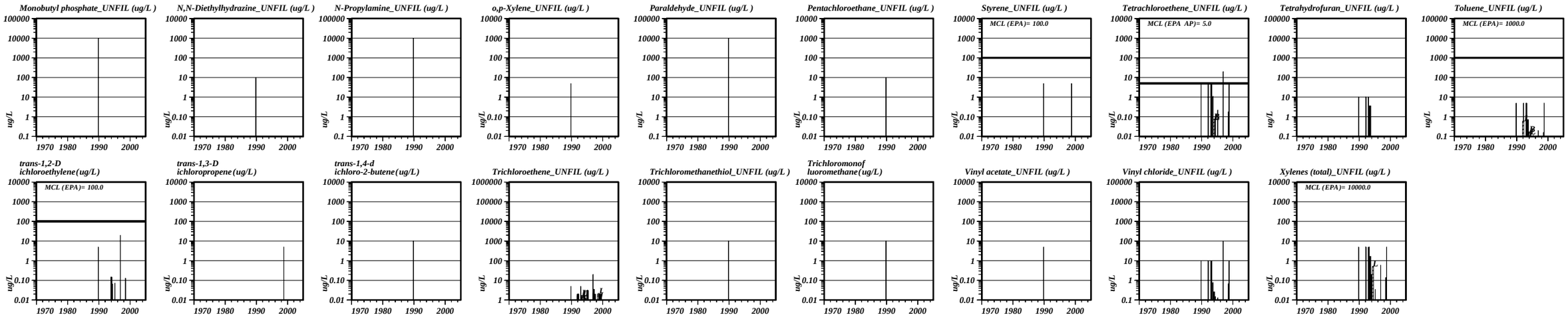
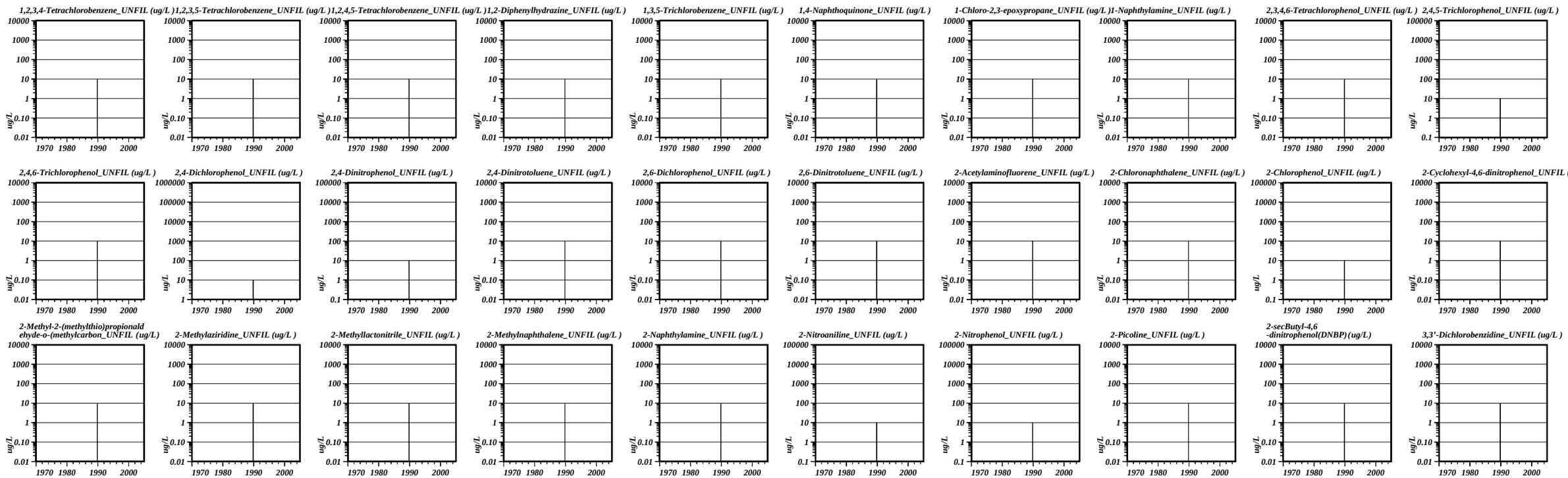
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-200-299 WELL#=299-W19-26

VOLATILE ORGANIC COMPOUNDS



SEMI-VOLATILE ORGANIC COMPOUNDS



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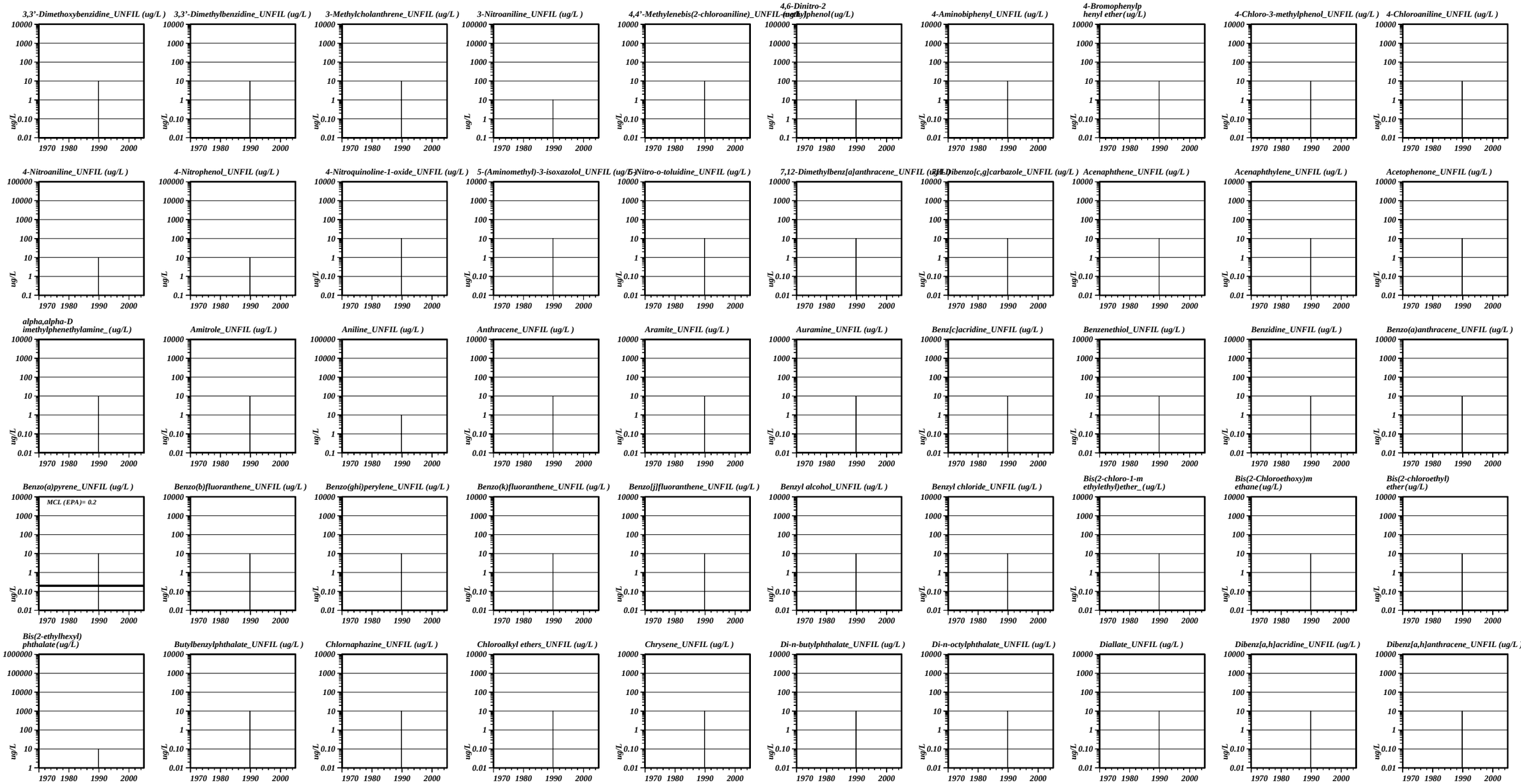
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-200-299 WELL#=299-W19-26

SEMI-VOLATILE ORGANIC COMPOUNDS



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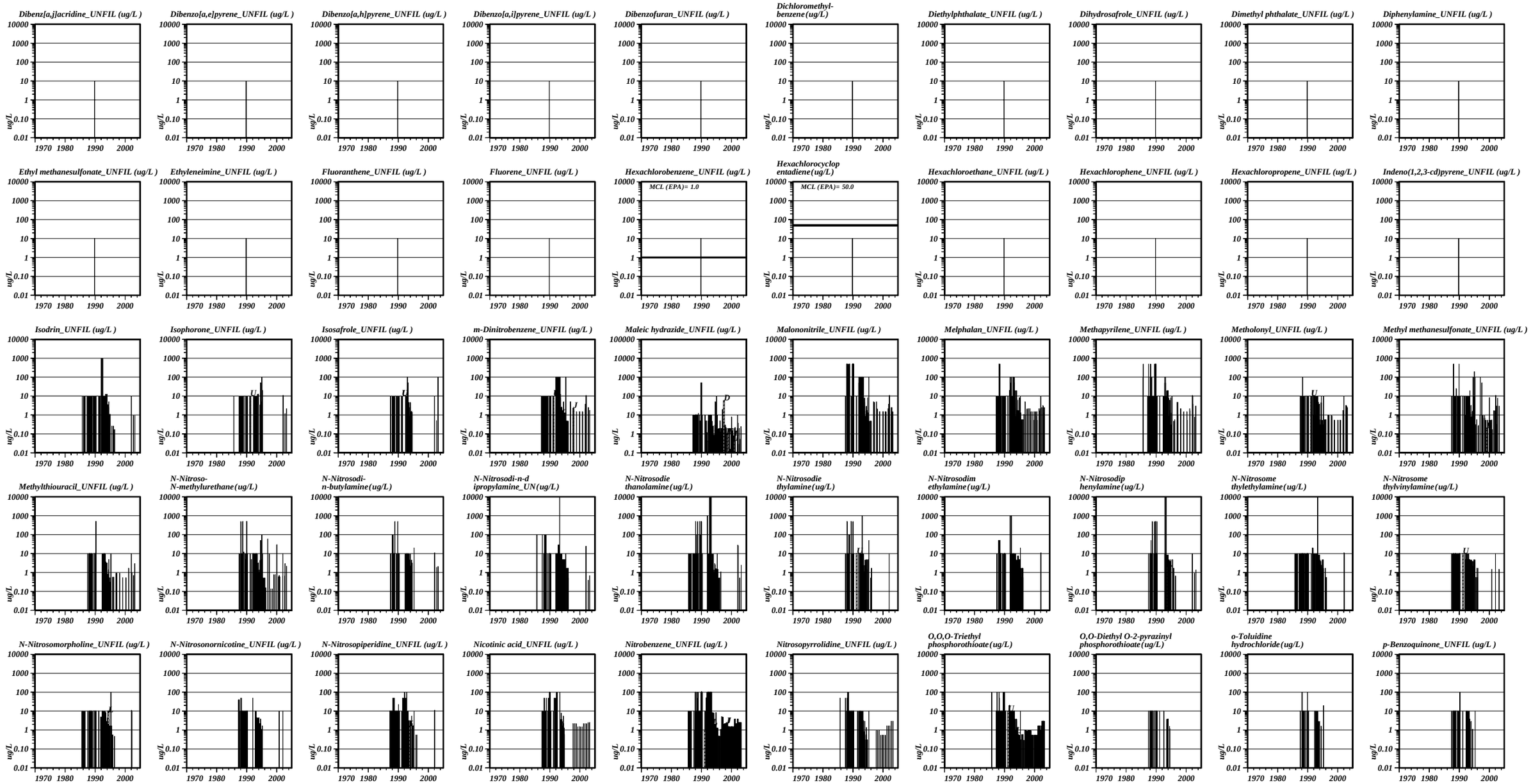
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-200-299 WELL#=299-W19-26

SEMI-VOLATILE ORGANIC COMPOUNDS



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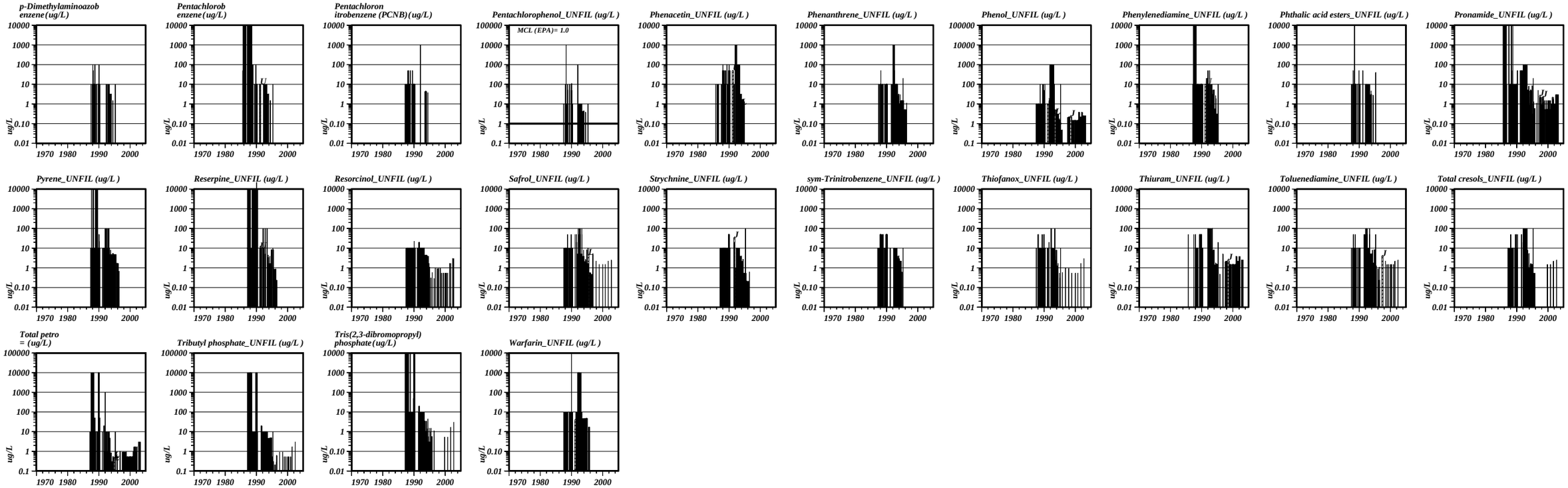
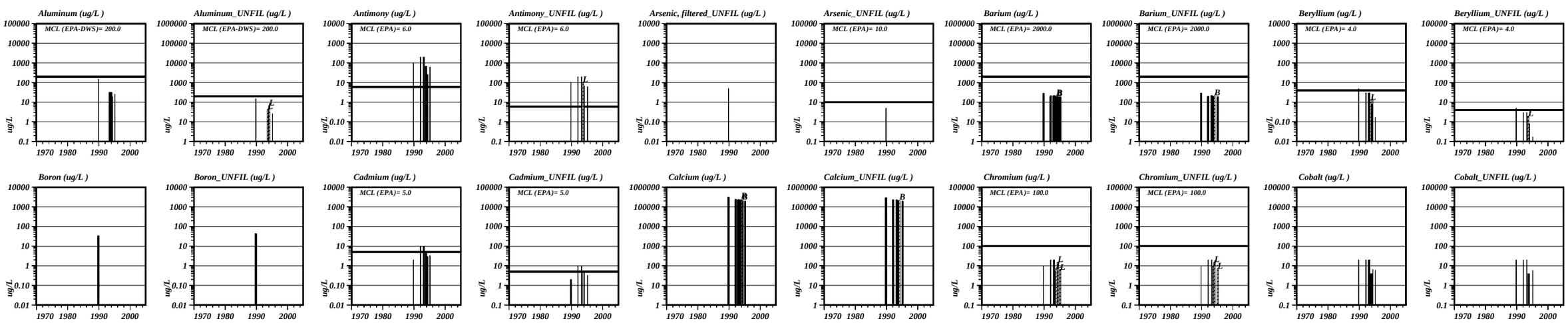
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-200-299 WELL#=299-W19-26

SEMI-VOLATILE ORGANIC COMPOUNDS



METALS & PHYSICAL PARAMETERS



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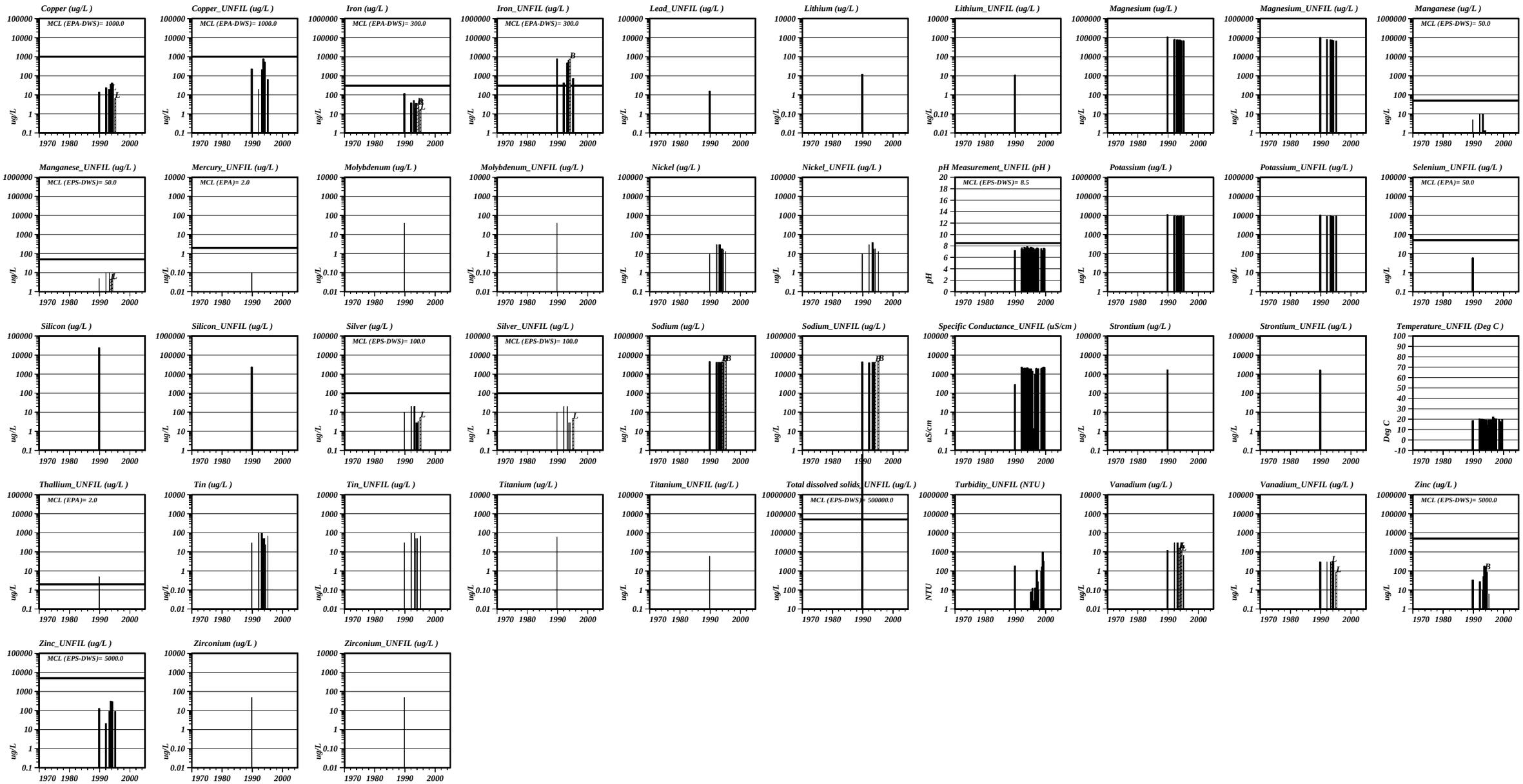
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-200-299 WELL#=299-W19-26

METALS & PHYSICAL PARAMETERS



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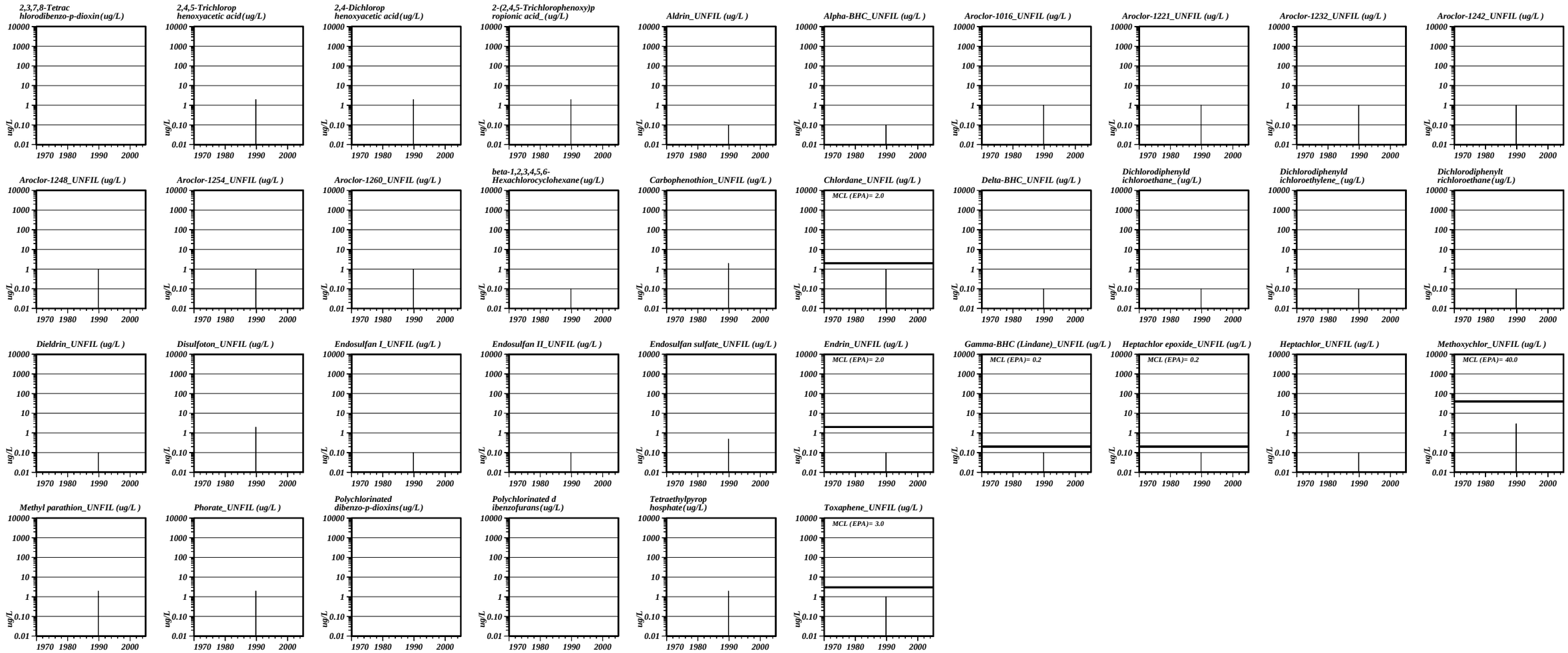
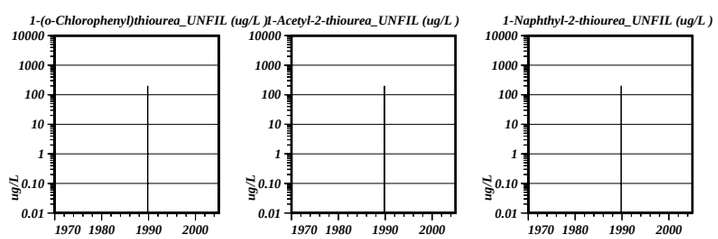
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-200-299 WELL#=299-W19-26

PEST/PCB, HERB, & DIOXINS



GENCHEM & ORGANICS & GENORGANICS



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